

The remaining operator control is a vertical centering control for the gated audio so the operator need not readjust the oscilloscope for every device under test. The audio out is gated so the operator will see only that portion of the audio which is of interest in the selection of devices for noise and "tilt" phenomena.

A/DA TEST FIXTURE

Procedures: Note: In all of the following procedures the Audio In switch is placed in the Gnd position to eliminate external noise from the test display.

"A" Test. In this procedure the A/B Test switch is placed in the "A" Test/Ungated Clock position. A device to be tested is placed in the zero -insertion-force socket and locked in with the lever. Oscilloscope controls are adjusted for stable display. Adjust Vertical Centering control on test fixture to center gated audio on display independently of oscilloscope trace centering controls. Function switch position #3 usually provides worst-case conditions for the "A" Test, but occasionally "tilt" will show up on some other position. When "tilt" is present, it may not necessarily be observed on all positions of the Function switch. "Tilt" is observed as any shift in the D.C. level of the noise floor from beginning to end of gated audio window and may produce audible distortion in the Harmony Synthesizer. "Tilt" values should be below 2 mv p-p, and values above 4mv p-p are not acceptable. Noise values should be below 5mv p-p and values above 10mv p-p are not acceptable.

"B" Test. All devices which pass the "A" Test are subjected to the "B" Test. Devices which pass "B" Testing are considered "B" devices. Those which fail "B" Testing are considered "A" category.

Place the A/B Test switch in the "B" Test/Gated Clock Position. Function switch position #1 usually provides worst-case conditions for the "B" Test. Any "tilt" observed during "B" Test should be below 2mv p-p and values above 4mv p-p are not acceptable. Noise values will be greater during "B" Test. Desired values are below 10mv p-p and values above 20mv p-p are not acceptable. If better noise values are possible under "B" Test conditions, we would like to hear about them!

Further information or clarification is available through Analog/Digital Associates, 2316 Fourth Street, Berkeley, CA 94710. (415) 548-1311. Ask for Reed Putnam or David Tarnowski.

